

Reverse Engineering ICs

ReCON 2012

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whoami

- Studied CE at TU Berlin
- PhD student - "Security in Telecommunications"
- IC security, crypto, low-cost attacks...
- Blog: <http://hwsec.net>

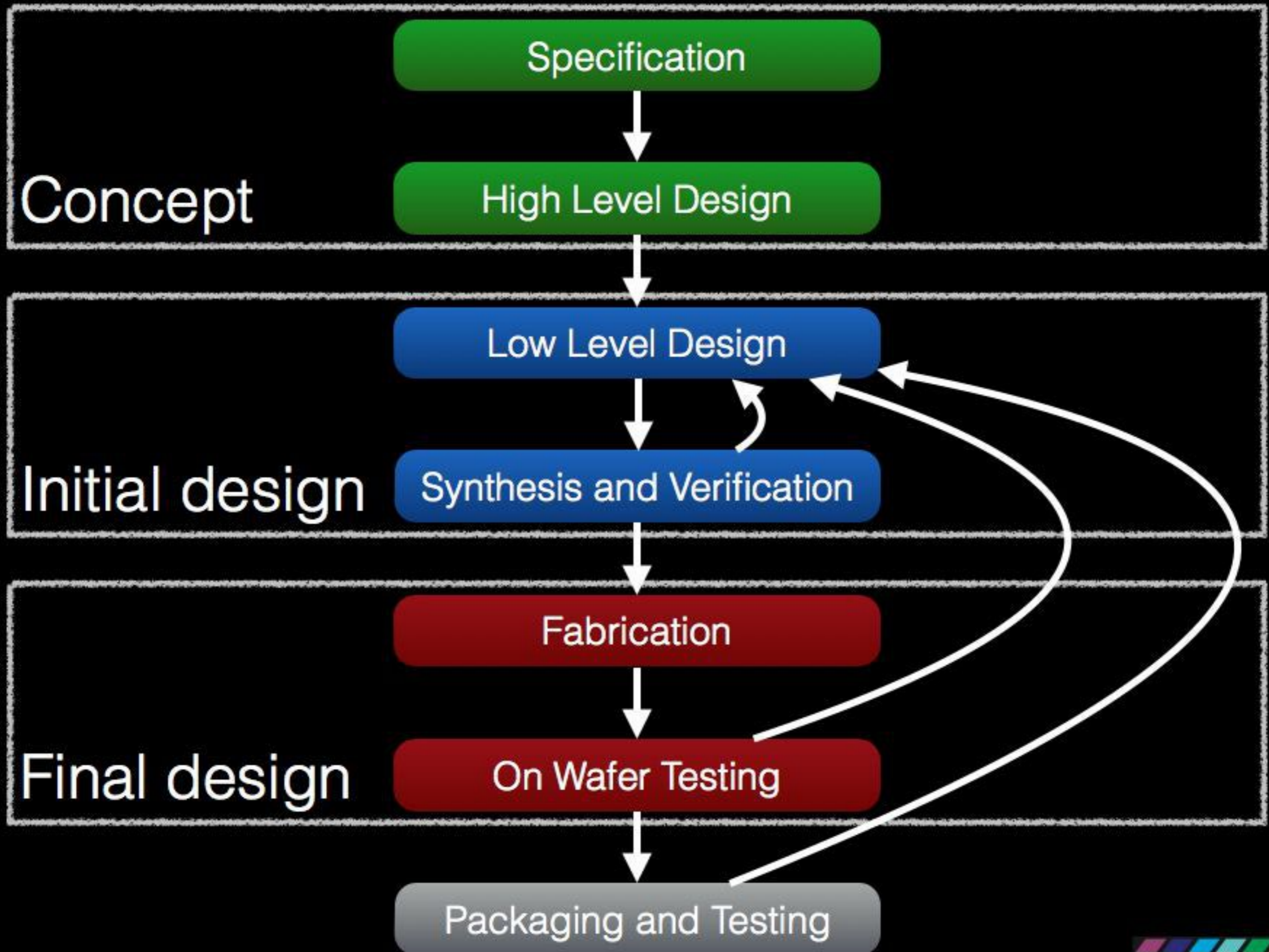
RTFPapers

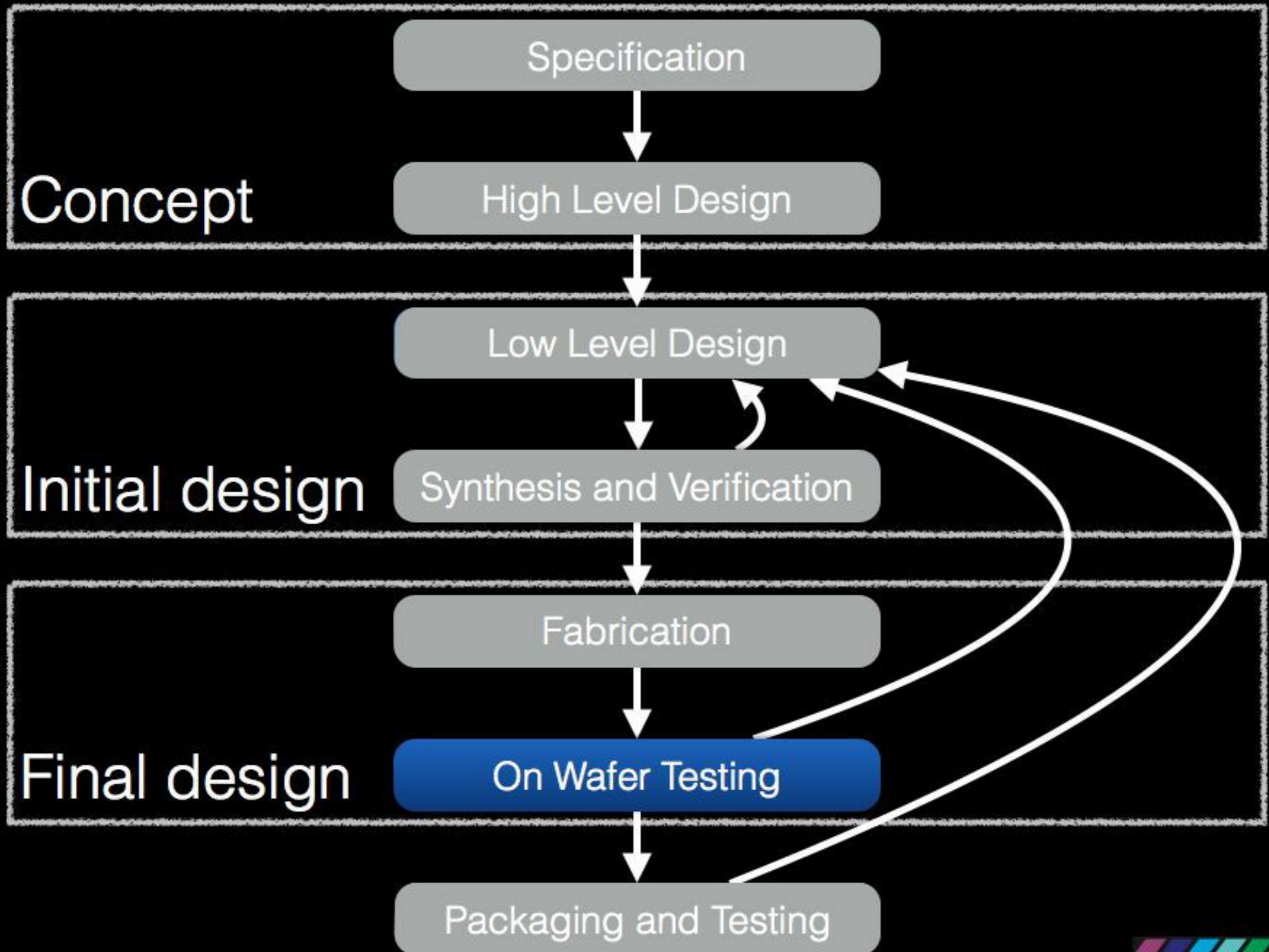
Functional IC Analysis
IEEE HOST 2012

Simple Photonic Emission Analysis of AES
CHES 2012

Story time with Dmitry

A brief introduction to failure analysis





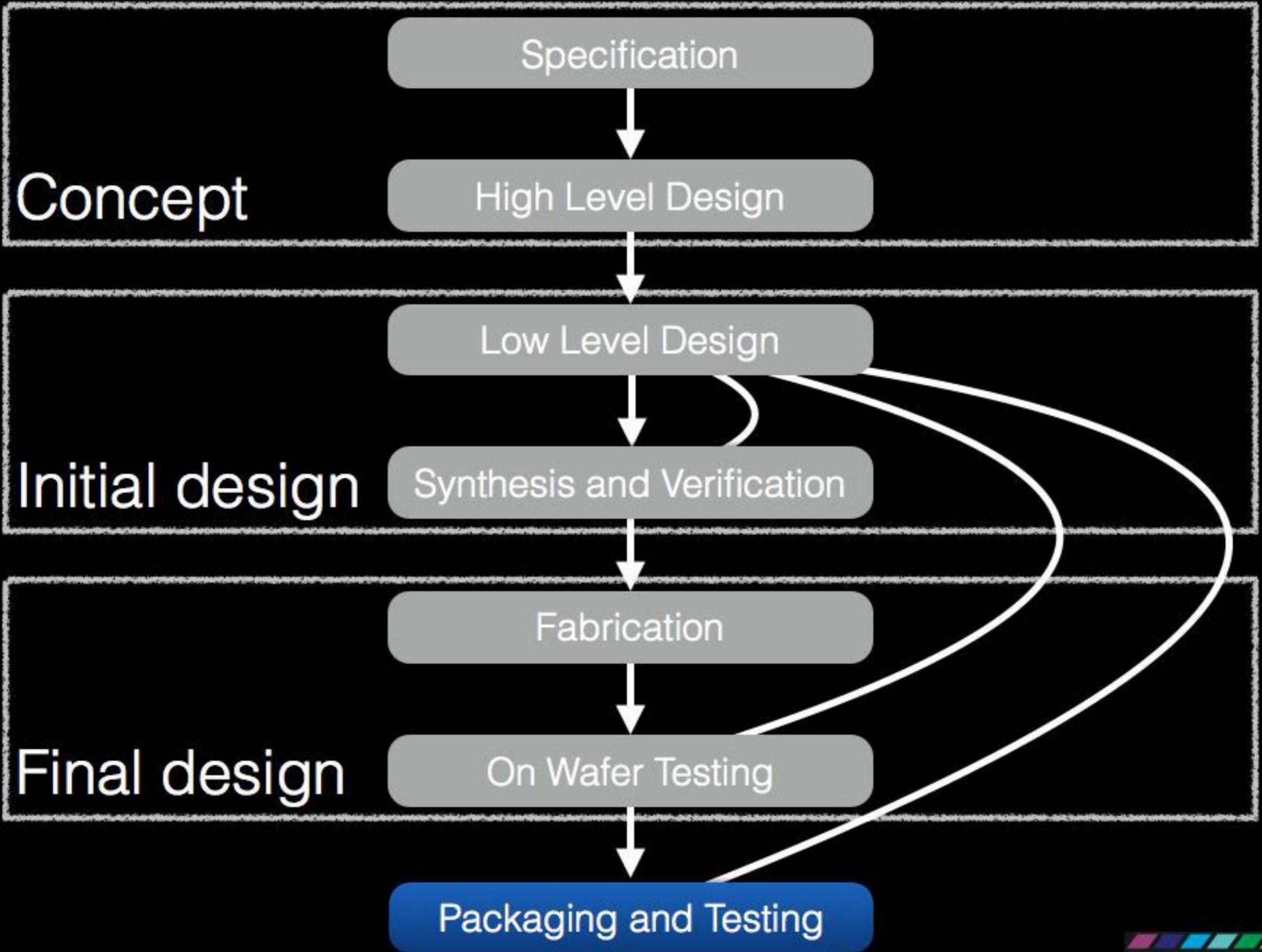
On wafer testing

Copyright: Verigy

Source: http://www.youtube.com/watch?v=de_LCVmJEE4

On-Wafer Testing

- Completely automated
- Pass/Fail Testing
- Test scan chains
- Can be performed during manufacturing



FIB Circuit Edit

Copyright: FEI

Source: <http://www.youtube.com/watch?v=CF5vCsmuiAk>

FIB

- Analyze quality of bonds
- Edit circuits
- Labor intensive, requires skilled operator
- > \$100,000

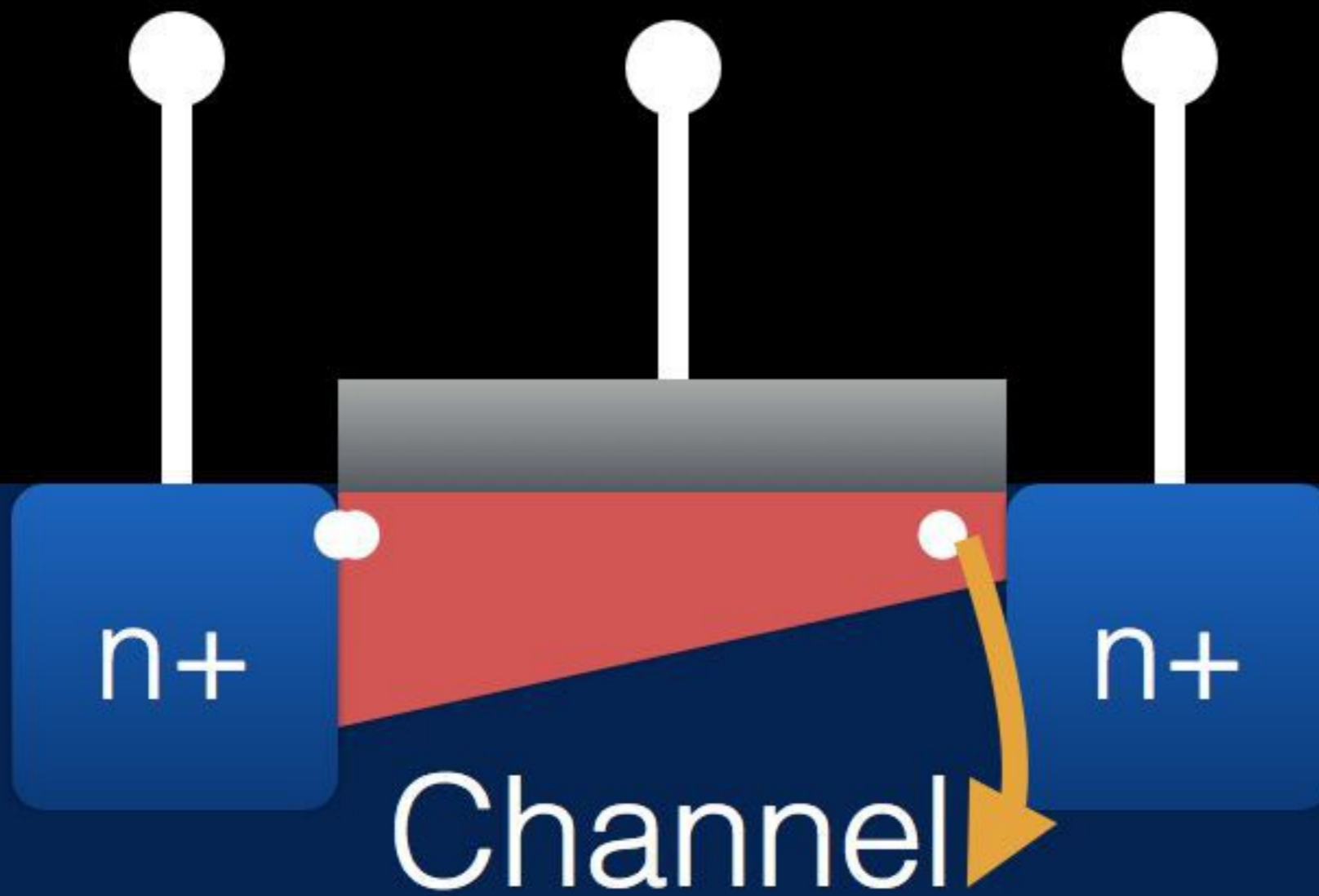
More Exotic Techniques

- Laser stimulation
- Atomic force microscopy
- ★ Photonic emission analysis

Source

Gate

Drain



Hamamatsu Phemos



- Can be used for optical emission analysis
- Backside is possible - no rebonding
- > \$1M

NIR CCD

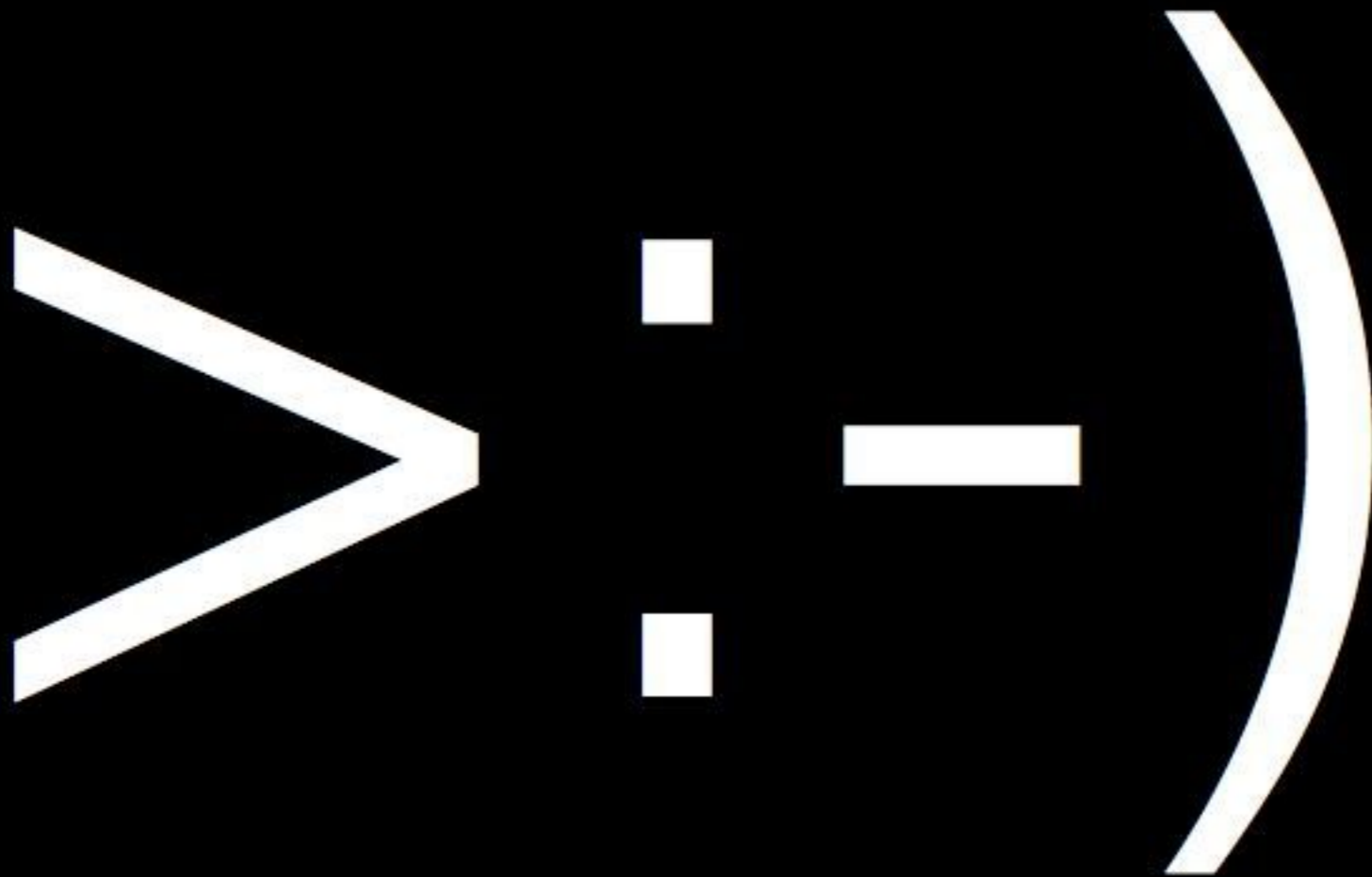


Microscope Optics



DUT

Reverse Engineering



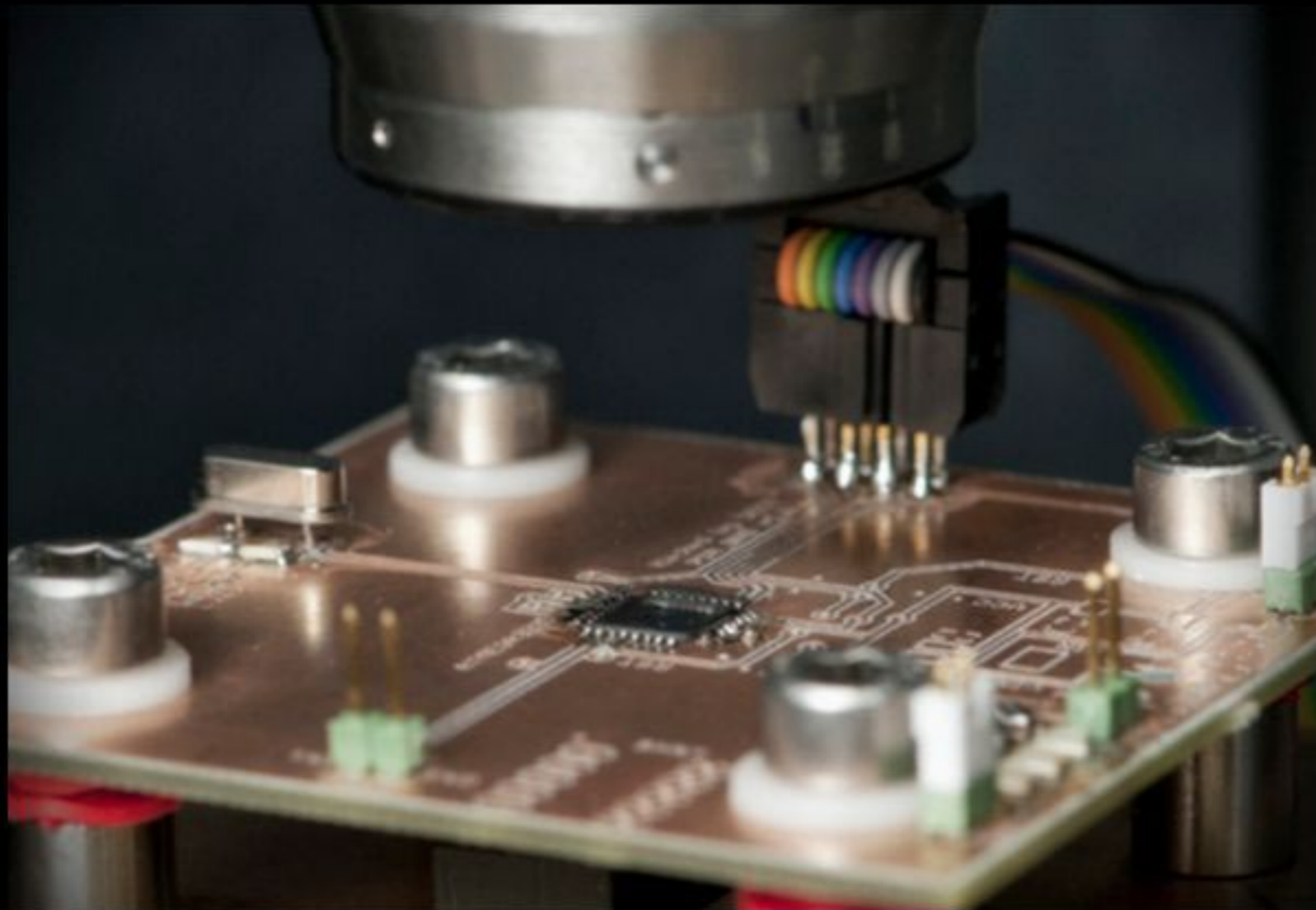
Frontside

$n+$

$n+$

Backside

Setup



A microscopic view of a circuit board, showing a grid of components and traces. A blue rectangular box highlights a central area containing the word "FLASH" in large, bold, blue capital letters. The background is a complex pattern of blue, green, and yellow, representing the underlying circuitry.

FLASH

A grayscale micrograph of a silicon die with various functional blocks highlighted by blue boxes. The largest box is labeled 'FLASH'. Below it, a box labeled 'SRAM' is positioned to the left of a vertical box labeled 'LOGIC'. To the right of the 'SRAM' box, the word 'LOGIC' is written horizontally. The background shows the intricate circuitry of the die.

FLASH

SRAM

LOGIC

LOGIC



Identifying logic

A grayscale micrograph of a silicon die with various functional blocks highlighted by blue boxes. The largest box is labeled 'FLASH'. Below it, a box labeled 'SRAM' is positioned to the left of a vertical box labeled 'LOGIC'. To the right of the 'SRAM' box, the word 'LOGIC' is written horizontally. The background shows the intricate circuitry of the die.

FLASH

SRAM

LOGIC

LOGIC



FLASH

SRAM

LOGIC

LOGIC

LOGIC

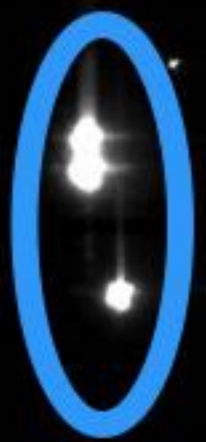


ldi r16,0x00

What to look at



```
.global infloop  
infloop: rjmp infloop ; to self
```



Memory map

```
; first parameter: r25:r24 - addr
; second parameter: r22 - value
.global memmap
memmap: movw r26,r24 ; addr to X
loop:   st   X,r22 ; write to [X]
        rjmp loop
```

0x100





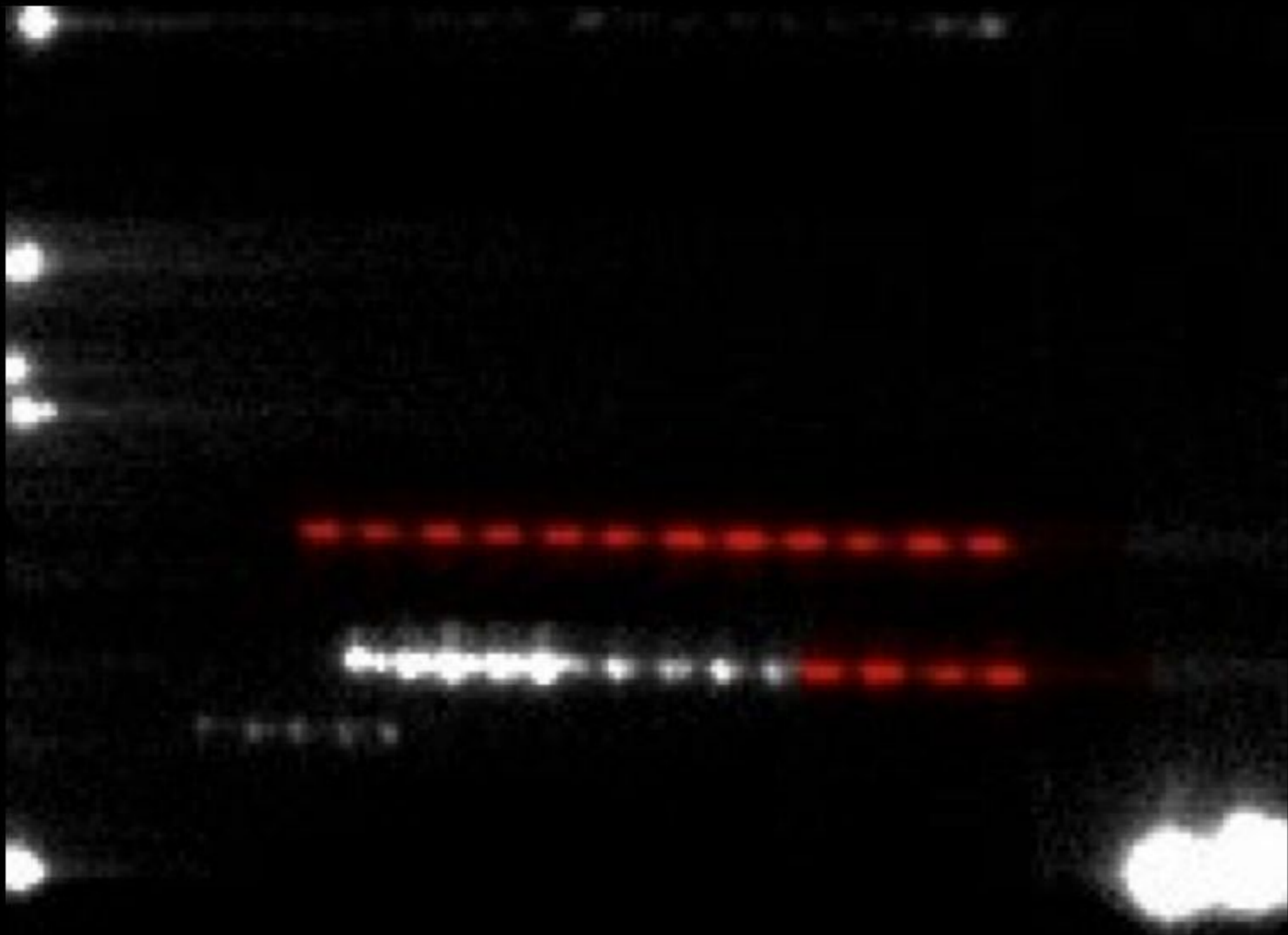
0x180	0x380	0x580	0x780
0x100	0x300	0x500	0x700
0x880	0x280	0x480	0x680
0x800	0x200	0x400	0x600

Branching logic


```
.global setclrz
setclrz:  sez ; set Z-flag
          clz ; clear Z-flag
          rjmp setclrz
```




Execution logic



0x0f5a: ldi r17,0x03



0x0f5a: ldi r17,0x03

0x0f5b: ldi r16,0x03

```
ldi r17, 0x01 ; 0xf6a - loop1
rjmp .-4 ; 0xf6c
ldi r17, 0x02 ; 0xf6e - loop2
rjmp .-4 ; 0xf70
ldi r17, 0x04 ; 0xf72 - loop3
rjmp .-4 ; 0xf74
```

Loop3 (0xf72)
Loop2 (0xf6e)
Loop1 (0xf6a)

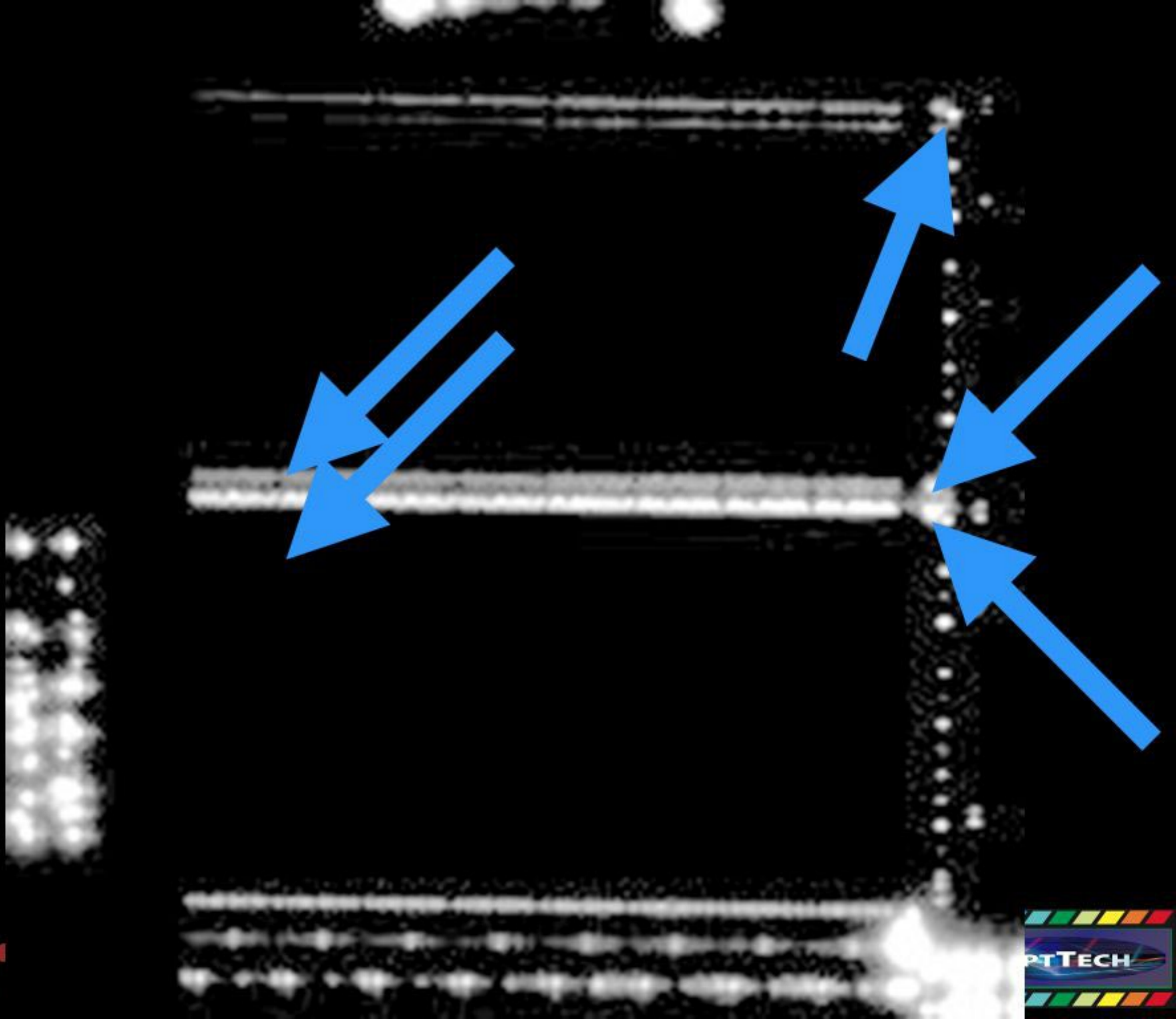
Reverse engineering ICs?

- There's an industry for that!
- FA is similar to reversing
- Lots of literature
- Low cost is possible

UART Hello World



memcpy





T-Mobile
54944671-9/185
0151

1. Enable AES interrupts (optional)
2. Select the AES direction, encryption or decryption.
3. Load the Key data block into the AES Key memory
4. Load the data block into the AES State memory
5. Start the encryption/decryption operation

progress.

Figure 23-2. The State memory with pointers and register



If more than one block is to be encrypted or decrypted **repeat** the procedure from step 3.

